Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/748,734	NAKAHARA, KEN	
Examiner	Art Unit	
Johannes P. Mondt	3663	

SEARCHED						
Class	Subclass	Date	Examiner			
		-				

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
			-			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
cf. Search History: 257/(79-103) 372/(43.01,46.01,46.013,46.015 and 29.013) 349/(42-53)	2/17/2006	JPM		
STIC search done by M. Sims (TC2800)	2/17/2006	JPM		
East, IEEE, INSPEC	2/17/2006	· JPM		